


<b>Search Notes</b>  	<b>Application/Control No.</b>  10617349	<b>Applicant(s)/Patent Under Reexamination</b>  WILLIAM ET AL.
	<b>Examiner</b>  Shin, John	<b>Art Unit</b>  4132

SEARCHED			
Class	Subclass	Date	Examiner
705	Text Only: 31, 19, 36R, 417	10/03/07	JYS
705	31,19, 36R, 417	9/19/08	V.F

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	10/03/07	JYS
West 2.0 updated	9/19/08	V.F

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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